

Prior Art

Figure 1

Run mode configured to make an on-chip assessment of amount of repaired memories and flag any device failed when it exceeds a certain limit

- build a counter as part of BISR which is thereafter loaded through a test pattern during production testing that establishes the threshold for pass/fail criteria

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Run power-on state machine configured to load a computed repair solution and thereafter test the memories for any additional failures and, if there are any, repair them (provided enough redundant elements are available)

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Figure 2

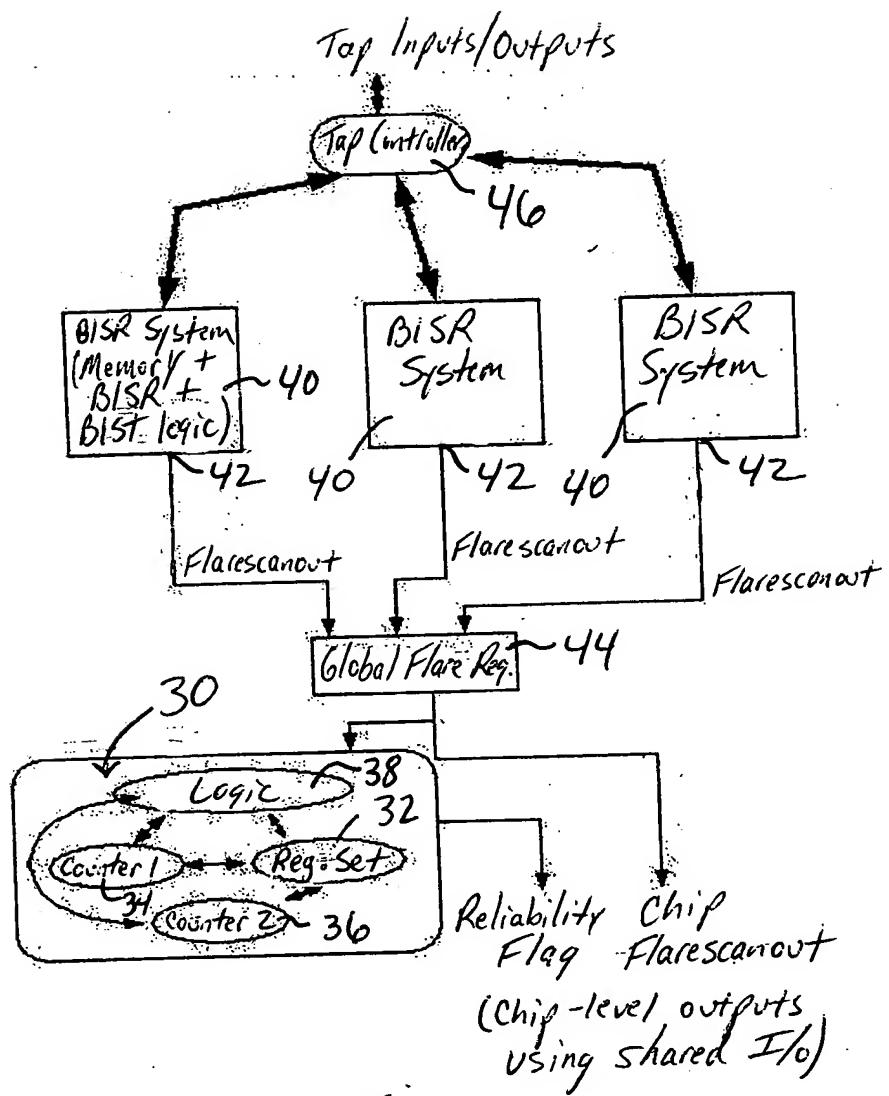


Figure 3